



FINAL CALL FOR PAPERS

ABSTRACTS DUE FEB 4, 2019

2019 International Image Sensor Workshop

Snowbird, Utah (USA)

Co-Chairs:

Nobukazu Teranishi

The 2017 International Image Sensor Workshop (IISW innovative work in the area of solid-state image sensor community. The workshop is intended for image sensor te As in the previous years, the workshop will emphasize ac information among the workshop participants in an information

Non-standard color patterns with special digital

Imaging system-on-a-chip , On-chip image processing

General Workshop Co-Chairs:

Daniel Van Blerkom Forza Silicon, USA

Yibing Michelle Wang Samsung, USA

Technical Program Chair:

Vladimir Korobov ON Semiconductor, USA

Technical Program Committee:

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EPFL, Switzerland

Bart Dierickx

Caeleste, Belgium

Neal Dutton ST Microelectronics, UK

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Samsung, South Korea

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Alexima, USA

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TowerJazz, Israel

Jiaiu Ma

Gigajot, USA

Pierre Magnan

ISAE, France

Shouleh Nikzad

JPL / CalTech, USA

Yusuke Oike

Sony, Japan

The 2019 International Image Sensor Workshop (IISW) provides all aspects innovative work in the area of solid-state image sensors and share new resulting the think action poster pages and share new resulting the area of solid-state image sensors and share new resulting the area of solid-state image sensors solid regard to the workshop includes all aspects and share new resulting the area of solid regard to the workshop includes all aspects and share new resulting the area of solid regard to the workshop includes all aspects are shared to the workshop includes all aspects are s community. Now in its 33rd year, the workshop is interestable for image sensor technologists; in order to encourage attendee interaction and a shared experience in first tendence is first tended; with the same solicited: acceptance preference given to workshop presenters. As is its tradition, the a a server a se emphasize an open exchange of information among participants in an information among participants in a participant among participants in a participant among participants in a participant among par

Committee: The scope of the workshop includes all aspects of electronicial regressions of the workshop includes all aspects of electronicial regressions. In addition to regular oral and poster papers, the works and invited trails and services are services are services and services are services and services are services are services and services are services and services are services are services and services are services and services are ser announcement of International Image Sensors Society (Hospinaward Winnerstigh image quality. Low noise. High sensitivity

Papers on the following topics are solicited:

Image Sensor Design and Performance

CMOS imagers, CCD imagers, SPAD sensors New and disruptive architectures

Global shutter image sensors

Low noise readout circuitry, ADC designs

Single photon sensitivity sensors

High frame rate image sensors

High dynamic range sensors

Low voltage and low power imagers

High image quality; Low noise; High sensitivity

Improved color reproduction

Non-standard color patterns with special digital processing Imaging system-on-a-chip, On-chip image processing

Pixels and Image Sensor Device Physics

New devices and pixel structures

Advanced materials

Ultra miniaturized pixels development, testing, and characterization

New device physics and phenomena

Electron multiplication pixels

Techniques for increasing QE, well capacity, reducing crosstalk, and improving angular response

Front side illuminated, back side illuminated, and stacked pixels and pixel arrays

Pixel simulation: Optical and electrical simulation, 2D and 3D, CAD for design and simulation, improved models

Bart Dierickx Caeleste, Belgiun Neal Dutton

Eric Fossum

Pixels and Image Sensor Device Physics Application Specific Imagers New devices and pixel structures

Image sensors and pixels for range semsing also, RGBZ, Strucklish Guidash Greo imagi Illira miniaturized pixels development, testing, and Imagase Ragenus the enhanced repeatives sensitivity (Melifonus) a R)

Sensors for Diversity January, mobil Elegton multiplication pixels and Burnsuk Kim Techniques for increasing CE, well capacity, mirroumbess cannot as reducing crosstalk, and improving angular response

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High Mis Belgium High energy photon and particle sensors (X-ray, radiation) Junichi Nakamura Line வால்லு அந்தி, Very large format imagers

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ABSTRACT SUBMISSION DEADL

Image sensor manufacturing and testing

New manufacturing techniques

Backside thinning

New characterization methods

Stacked imagers, 3D integration

On-chip optics

Advanced optical path, Color filters, Microlens, Light guides

Nanotechnologies for Imaging

Wafer level cameras

Packaging and testing; Reliability, Yield, Cost

Defects: Leakage current.

Radiation damage and radiation hard imagers

Appl Imag etc. Imag (NIR, came Array imagi

aeno radia Multi Imag

New

Back On-c Light

Wafe Relia Defe

Hidekazu Takahashi

Canon, Japan

Xinyang Wang

Gpixel, China

Dun-Nian Yaung

TSMC, Taiwan

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Thayer School of Engineering at Dartmouth, USA

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University of Hyogo, Japan

Albert Theuwissen

Harvest Imaging, Belgium / Delft University of Technology, The Netherlands

Daniel Van Blerkom

Forza Silicon, USA

Yibing Michelle Wang

Samsung, USA

Submission of abstracts:

An abstract should consist of a single page of maximum 500-words text with up to two pages of illustrations, and include authors' name(s) and affiliation, mailing address, telephone and e-mail address. The deadline for abstract submission is **February 4, 2019 (PST)**.

To submit an abstract, please go to: https://cmt3.research.microsoft.com/IISW2019

The first time you visit, you'll need to click on "Create Account". Once you create and verify your account with your email address, you will be able to submit abstracts by logging in and clicking "Create New Submission".

Please visit http://imagesensors.org/CFP2019 for complete instructions and any updates to the abstract and paper submission procedures.

Abstracts will be considered on the basis of originality and quality. High quality papers on work in progress are also welcome. Abstracts will be reviewed confidentially by the Technical Program Committee and the IISS Board.

Authors will be notified of the acceptance of their abstract by March 14, 2019.

Final-form 4-page paper submission date is May 3, 2019.

Presentation material submission date is June 14, 2019.

Location:

The IISW 2019 will be held at the Snowbird Resort, Utah (USA). This serene mountain resort is only 40 minutes from Salt Lake City International Airport, and in addition to excellent meeting space provides summer mountain activities and a summit aerial tram.

Registration, Workshop fee, and Hotel Reservation:

Registration details and hotel reservation information will be provided in the Final Announcement of the Workshop.

Forthcoming announcements and additional information will be posted on the **2019 Workshop page** of the International Image Sensor Society website at:

http://www.imagesensors.org/